

L Number	Hits	Search Text	DB	Time stamp
12	1290	445/3,24.ccls.	USPAT; US-PGPUB	2003/06/14 13:51
13	10	445/3,24.ccls. and ((light near2 (emitting emission emitter) near2 (dispalay device panel)) LED ((EL electroluminescen\$2) near2 (display device panel))) and (electrode cathode anode) and (xray x-ray (x near2 ray) (electromagnetic near2 (field charge energy wave source))) and (measurement measur\$3 detect\$3 inspect\$3 test\$3)	USPAT; US-PGPUB	2003/06/14 13:59
15	7	438/10,14-17.ccls. and ((light near2 (emitting emission emitter) near2 (dispalay device panel)) LED ((EL electroluminescen\$2) near2 (display device panel))) and (electrode cathode anode) and ((xray x-ray (x near2 ray) electromagnetic) near2 (field charge energy wave source)) and (measurement measur\$3 detect\$3 inspect\$3 test\$3)	USPAT; US-PGPUB	2003/06/14 14:03
16	36	324/500-537,750-765.ccls. and ((light near2 (emitting emission emitter) near2 (dispalay device panel)) LED ((EL electroluminescen\$2) near2 (display device panel))) and (electrode cathode anode) and ((xray x-ray (x near2 ray) electromagnetic) near2 (field charge energy wave source)) and (measurement measur\$3 detect\$3 inspect\$3 test\$3)	USPAT; US-PGPUB	2003/06/14 14:14
17	25	((light near2 (emitting emission emitter) near2 (dispalay device panel)) LED ((EL electroluminescen\$2) near2 (display device panel))) and (electrode cathode anode) and ((xray x-ray (x near2 ray) electromagnetic) near2 (field charge energy wave source)) and (measurement measur\$3 detect\$3 inspect\$3 test\$3)	EPO; JPO; DERWENT	2003/06/14 17:34
18	416	(445/\$.ccls. 324/\$.ccls. 438/\$.ccls.) and ((substrate semiconductor) same (electrode cathode anode)) and ((xray x-ray (x near2 ray) electromagnetic) near2 (field charge energy wave source)) and ((measurement measur\$3 detect\$3 inspect\$3 test\$3) with (voltage current power (electric near2 field)))	USPAT; US-PGPUB	2003/06/14 17:21
19	12	5103182.URPN.	USPAT	2003/06/14 14:56
20	5	("4704576" "4767982" "4818930" "4866370" "4868490").PN.	USPAT	2003/06/14 14:58
21	2	5897378.URPN.	USPAT	2003/06/14 16:31
22	7	("4430151" "4902631" "4975141" "5082517" "5215588" "5536359" "5770097").PN.	USPAT	2003/06/14 16:32
23	3	("3715667" "4634963" "5424633").PN.	USPAT	2003/06/14 17:16
24	0	6320401.URPN.	USPAT	2003/06/14 17:16
25	331	((445/\$.ccls. 324/\$.ccls. 438/\$.ccls.) and ((substrate semiconductor) same (electrode cathode anode)) and ((xray x-ray (x near2 ray) electromagnetic) near2 (field charge energy wave source)) and ((measurement measur\$3 detect\$3 inspect\$3 test\$3) with (voltage current power (electric near2 field)))) not @ad>20010530	USPAT; US-PGPUB	2003/06/14 17:33
26	662	438/17.ccls.	USPAT; US-PGPUB	2003/06/14 17:34
27	81	438/17.ccls. and (electrode cathode anode) and ((xray x-ray electron light laser (x near2 ray) electromagnetic) near2 (field charge beam energy wave source)) and (measurement measur\$3 detect\$3 inspect\$3 test\$3)	USPAT; US-PGPUB	2003/06/14 17:39
28	76	438/17.ccls. and (electrode cathode anode) and ((xray x-ray electron light laser (x near2 ray) electromagnetic) near2 (field charge beam energy wave source)) and ((measurement measur\$3 detect\$3 inspect\$3 test\$3) same (current voltage electric\$3))	USPAT; US-PGPUB	2003/06/14 17:57
30	466	((xray x-ray electron light laser (x near2 ray) electromagnetic) near2 (field charge beam energy wave source)) and ((measurement measur\$3 detect\$3 inspect\$3 test\$3) same (current voltage electric\$3)) and ((gas gaseous) with ioniz\$3) and (445/\$.ccls. 438/\$.ccls. 257/\$.ccls. 324/\$.ccls.)	USPAT; US-PGPUB	2003/06/14 18:04
29	55	((xray x-ray electron light laser (x near2 ray) electromagnetic) near2 (field charge beam energy wave source)) and ((measurement measur\$3 detect\$3 inspect\$3 test\$3) same (current voltage electric\$3)) and ((gas gaseous) with ioniz\$3)	EPO; JPO; DERWENT	2003/06/14 18:20

31	369	((xray x-ray electron light laser (x near2 ray) electromagnetic) near2 (field charge beam energy wave source)) and ((measurement measur\$3 detect\$3 inspect\$3 test\$3) same (current voltage electric\$3)) and ((gas gaseous) with ioniz\$3) and (445/\$.ccls. 438/\$.ccls. 324/\$.ccls.)	USPAT; US-PGPUB	2003/06/14 18:05
14	10	438/10,14-17.ccls. and ((light near2 (emitting emission emitter) near2 (dispalay device panel)) LED ((EL electroluminescen\$2) near2 (display device panel))) and (electrode cathode anode) and (xray x-ray (x near2 ray) (electromagnetic near2 (field charge energy wave source))) and (measurement measur\$3 detect\$3 inspect\$3 test\$3)	USPAT; US-PGPUB	2003/06/14 18:24
35	780	TFT same (measurement measur\$3 detect\$3 inspect\$3 test\$3)	EPO; JPO; DERWENT	2003/06/14 18:20
36	387	TFT same (measurement measur\$3 detect\$3 inspect\$3 test\$3) same (display device)	EPO; JPO; DERWENT	2003/06/14 18:24
37	48	TFT same (measurement measur\$3 detect\$3 inspect\$3 test\$3) same (display device) and ((xray x-ray electron light laser (x near2 ray) electromagnetic) near2 (field charge beam energy wave source))	EPO; JPO; DERWENT	2003/06/14 18:26
38	141	TFT same (measurement measur\$3 detect\$3 inspect\$3 test\$3) same (display device) and ((xray x-ray electron light laser (x near2 ray) electromagnetic) near2 (field charge beam energy wave source)) and (445/\$.ccls. 438/\$.ccls. 324/\$.ccls.)	USPAT; US-PGPUB	2003/06/14 18:50
39	1	5982190.URPN.	USPAT	2003/06/14 18:39
40	4	("5276400" "5371459" "5432461" "5504438").PN.	USPAT	2003/06/14 18:40
41	1	TFT same ((measurement measur\$3 detect\$3 inspect\$3 test\$3) with (current voltage electric electrical)) same (ioniz\$3) and (445/\$.ccls. 438/\$.ccls. 324/\$.ccls.)	USPAT; US-PGPUB	2003/06/14 18:52
42	228	((((measurement measur\$3 detect\$3 inspect\$3 test\$3) with (current voltage electric electrical)) same (ioniz\$3)) and (445/\$.ccls. 438/\$.ccls. 324/\$.ccls.) and (TFT electrode) and (display device panel)	USPAT; US-PGPUB	2003/06/14 18:59
43	264	semiconductor and (EL electroluminescent (light near2 (emitting emission emitter))) and electrode and (inspect\$3 same substrate)	USPAT; US-PGPUB	2003/06/14 19:35
44	175	(semiconductor same (TFT electrode)) and (EL electroluminescent (light near2 (emitting emission emitter))) and (inspect\$3 same substrate)	USPAT; US-PGPUB	2003/06/14 19:36